



Form 1449 (Modified)

Information Disclosure Statement By Applicant

(Use Several Sheets if Necessary)

Atty Docket No.	LAM1P128	RECEIVED
Application No.:	09/440,794	APR 19 2001
Applicant	Bailey III et al.	
Filing Date	November 15, 1999	
Group	1765	TC 1700
		#5

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
MAT	A.	5,810,932	09/1998	Ueda et al.			
	B.						
	C.						
	D.						
	E.						

Foreign Patent or Published Foreign Patent Application

Examiner Initial		Document No.	Publication Date	Country or Patent Office	Class	Sub-Class	Translation Yes	Translation No
MAT	F.	EP 0 821 397 A2	✓ 01/1998	EPO				
MAT	G.	WO 99/50886	✓ 10/1999	PCT				
	H.							
	I.							
	J.							
	K.							

Other Documents

Examiner Initial	No.	Author, Title, Place (e.g. Journal) of Publication, Date
MAT	L.	Japanese Application No. 04094953, filed March 1992, entitled "PLASMA DAMAGE REDUCTION AND PLASMA PROCESSOR," by Minegishi Kazushige, Patent Abstracts of Japan, Vol. 18, No. 33.
MAT	M.	Japanese Application No. 08255259, filed August 1996, entitled "SHALLOW MAGNETIC FIELD FOR IMPROVING PLASMA PROCESSING BY THE CIRCULATION OF ELECTRONS," by Michael Welch, Patent Abstracts of Japan, Vol. 1999, No. 7.
	N.	
	O.	
	P.	
	Q.	
	R.	
	S.	
Examiner		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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Please Several Sheets if Necessary)

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
MAA	A.	4,948,458	08/1990	Ogle		100	08/1990
MAA	B.	4,990,229	02/1991	Campbell et al.		100	02/1991
MAA	C.	5,091,049	02/1992	Campbell et al.		100	02/1992
MAA	D.	5,122,251	06/1992	Campbell et al.		100	06/1992
MAA	E.	5,421,891	06/1995	Campbell et al.		100	06/1995
MAA	F.	5,429,070	07/1995	Campbell et al.		100	07/1995
MAA	G.	5,587,038	12/1996	Cecchi et al.		100	12/1996

Foreign Patent or Published Foreign Patent Application

Examiner Initial		Document No.	Publication Date	Country or Patent Office	Class	Sub-Class	Translation Yes No
MAA	H.	0 838 843 A2	04/1998	EPO			
	I.						
	J.						

Other Documents

Examiner Initial	No.	Author, Title, Place (e.g. Journal) of Publication, Date
	K.	
	L.	
	M.	
	N.	
	O.	
	P.	
	Q.	
	R.	
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